

ON Semiconductor®

## **FAN3213 / FAN3214 Dual-4 A, High-Speed, Low-Side Gate Drivers**

## **Features**

- Industry-Standard Pin Out
- 4.5 to 18 V Operating Range
- 5 A Peak Sink/Source at  $V_{DD} = 12$  V
- $\blacksquare$  4.3 A Sink / 2.8 A Source at  $V_{\text{OUT}} = 6$  V
- TTL Input Thresholds
- Tw o Versions of Dual Independent Drivers: Dual Inverting (FAN3213)
	- Dual Non-Inverting (FAN3214)
- Internal Resistors Turn Driver Off If No Inputs
- MillerDrive™ Technology
- 12 ns / 9 ns Typical Rise/Fall Times with 2.2 nF Load
- Typical Propagation Delay Under 20 ns Matched w ithin 1 ns to the Other Channel
- Double Current Capability by Paralleling Channels
- Standard SOIC-8 Package
- Rated from –40°C to +125°C Ambient
- Automotive Qualified to AEC-Q100 (F085 Version)

### **Description**

The FA N3213 and FAN3214 dual 4 A gate drivers are designed to drive N-channel enhancement-mode MOSFETs in low -side sw itching applications by providing high peak current pulses during the short sw itching intervals. They are both available w ith TTL input thresholds. Internal circuitry provides an undervoltage lockout function by holding the output LOW until the supply voltage is w ithin the operating range. In addition, the drivers feature matched internal propagation delays betw een A and B channels for applications requiring dual gate drives w ith critical timing, such as synchronous rectifiers. This also enables connecting tw o drivers in parallel to effectively double the current capability driving a single MOSFET.

The FA N3213/14 drivers incorporate MillerDrive™ architecture for the final output stage. This bipolar-MOSFET combination provides high current during the Miller plateau stage of the MOSFET turn-on / turn-off process to minimize sw itching loss, w hile providing railto-rail voltage sw ing and reverse current capability.

The FAN3213 offers two inverting drivers and the FA N3214 offers two non-inverting drivers. Both are offered in a standard 8-pin SOIC package.

## **Applications**

- Sw itch-Mode Pow er Supplies
- High-Efficiency MOSFET Sw itching
- Synchronous Rectifier Circuits
- DC-to-DC Converters
- Motor Control
- Automotive-Qualified Systems (F085 version)



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## **Ordering Information**



**Note:** 

1. Qualified to AEC-Q100

## **Package Outlines**



## **Thermal Characteristics**(2)



#### **Notes:**

2. Estimates derived from thermal simulation; actual values depend on the application.

- 3. Theta\_JL  $(\Theta_{JL})$ : Thermal resistance betw een the semiconductor junction and the bottom surface of all the leads (including any thermal pad) that are typically soldered to a PCB.
- 4. Theta\_JT  $(\Theta_{\text{JT}})$ : Thermal resistance betw een the semiconductor junction and the top surface of the package, assuming it is held at a uniform temperature by a top-side heatsink.
- 5. Theta\_JA (ΘJA): Thermal resistance betw een junction and ambient, dependent on the PCB design, heat sinking, and airflow . The value given is for natural convection w ith no heatsink, using a 2S2P board, as specified in JEDEC standards JESD51-2, JESD51-5, and JESD51-7, as appropriate.
- 6. Psi\_JB ( $\Psi_{JB}$ ): Thermal characterization parameter providing correlation betw een semiconductor junction temperature and an application circuit board reference point for the thermal environment defined in Note 5. For the SOIC-8 package, the board reference is defined as the PCB copper adjacent to pin 6.
- 7. Psi $JT$  ( $\Psi_{JT}$ ): Thermal characterization parameter providing correlation betw een the semiconductor junction temperature and the center of the top of the package for the thermal environment defined in Note 5.

## **Pin Configurations**



**Figure 3. Pin Configurations (Repeated)**

## **Pin Definitions**



## **Output Logic**





#### **Note:**

9. Default input signal if no external connection is made.



## **Absolute Maximum Ratings**

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.



## **Recommended Operating Conditions**

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. ON Semiconductor does not recommend exceeding them or designing to Absolute Maximum Ratings.



## **Electrical Characteristics**

Unless otherw ise noted, V<sub>DD</sub>=12 V, T<sub>J</sub>=-40°C to +125°C. Currents are defined as positive into the device and negative out of the device.



*Continued on the following page…*

## **Electrical Characteristics** (Continued)

Unless otherwise noted,  $V_{DD}=12$  V,  $T_J=-40^{\circ}C$  to +125°C. Currents are defined as positive into the device and negative out of the device.



#### **Notes:**

10. Not tested in production.

11. See Timing Diagrams of Figure 6 and Figure 7.

12. Apply only to Automotive Version(FAN321xTMX\_F085)



**Figure 6. Non-Inverting Timing Diagram Figure 7. Inverting Timing Diagram**













#### **Notes:**

- 13. For any inverting inputs pulled low , non-inverting inputs pulled high, or outputs driven high; static IDD increases by the current flow ing through the corresponding pull-up/dow n resistor show n in Figure 4 and Figure 5.
- 14. The initial spike in each current w aveform is a measurement artifact caused by the stray inductance of the current-measurement loop.

#### **Test Circuit**



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## **Applications Information**

#### **Input Thresholds**

The FAN3213 and the FAN3214 drivers consist of tw o identical channels that may be used independently at rated current or connected in parallel to double the individual current capacity.

The input thresholds meet industry-standard TTL-logic thresholds independent of the  $V_{DD}$  voltage, and there is a hysteresis voltage of approximately 0.4 V. These levels permit the inputs to be driven from a range of input logic signal levels for w hich a voltage over 2 V is considered logic HIGH. The driving signal for the TTL inputs should have fast rising and falling edges w ith a slew rate of 6 V/µs or faster, so a rise time from 0 to 3.3 V should be 550 ns or less. With reduced slew rate, circuit noise could cause the driver input voltage to exceed the hysteresis voltage and retrigger the driver input, causing erratic operation.

#### **Static Supply Current**

In the I<sub>DD</sub> (static) typical performance characteristics show n in Figure 8 and Figure 9, each curve is produced w ith both inputs floating and both outputs LOW to indicate the low est static I<sub>DD</sub> current. For other states, additional current flow s through the 100  $k\Omega$  resistors on the inputs and outputs show n in the block diagram of each part *(see Figure 4 and Figure 5)*. In these cases, the actual static I<sub>DD</sub> current is the value obtained from the curves plus this additional current.

#### **MillerDrive™ Gate Drive Technology**

FA N3213 and FA N3214 gate drivers incorporate the MillerDrive™ architecture show n in Figure 28. For the output stage, a combination of bipolar and MOS devices provide large currents over a w ide range of supply voltage and temperature variations. The bipolar devices carry the bulk of the current as OUT sw ings betw een 1/3 to  $2/3$   $V_{DD}$  and the MOS devices pull the output to the HIGH or LOW rail.

The purpose of the MillerDrive™ architecture is to speed up sw itching by providing high current during the Miller plateau region w hen the gate-drain capacitance of the MOSFET is being charged or discharged as part of the turn-on / turn-off process.

For applications w ith zero voltage sw itching during the MOSFET turn-on or turn-off interval, the driver supplies high peak current for fast sw itching even though the Miller plateau is not present. This situation often occurs in synchronous rectifier applications because the body diode is generally conducting before the MOSFET is sw itched ON.

The output pin slew rate is determined by  $V_{DD}$  voltage and the load on the output. It is not user adjustable, but a series resistor can be added if a slow er rise or fall time at the MOSFET gate is needed.



**Figure 28. MillerDrive™ Output Architecture**

#### **Under-Voltage Lockout**

The FAN321x startup logic is optimized to drive groundreferenced N-channel MOSFETs w ith an under-voltage lockout (UVLO) function to ensure that the IC starts up in an orderly fashion. When  $V_{DD}$  is rising, yet below the 3.9 V operational level, this circuit holds the output LOW, regardless of the status of the input pins. After the part is active, the supply voltage must drop 0.2 V before the part shuts dow n. This hysteresis helps prevent chatter when low  $V_{DD}$  supply voltages have noise from the pow er sw itching. This configuration is not suitable for driving high-side P-channel MOSFETs because the low output voltage of the driver w ould turn the P-channel MOSFET on with  $V_{DD}$  below 3.9 V.

### **V<sub>DD</sub>** Bypass Capacitor Guidelines

To enable this IC to turn a device ON quickly, a local high-frequency bypass capacitor,  $C_{BYP}$ , w ith low  $ESR$  and ESL should be connected betw een the VDD and GND pins w ith minimal trace length. This capacitor is in addition to bulk electrolytic capacitance of 10 µF to 47 µF commonly found on driver and controller bias circuits.

A typical criterion for choosing the value of CBYP is to keep the ripple voltage on the  $V_{DD}$  supply to  $\leq 5\%$ . This is often achieved with a value  $\geq 20$  times the equivalent load capacitance  $C_{EQV}$ , defined here as  $Q_{GATE}/V_{DD}$ . Ceramic capacitors of  $0.1 \mu F$  to  $1 \mu F$  or larger are common choices, as are dielectrics, such as X5R and X7R, w ith good temperature characteristics and high pulse current capability.

If circuit noise affects normal operation, the value of  $C_{\text{BYP}}$  may be increased, to 50-100 times the  $C_{\text{EQV}}$ , or C<sub>BYP</sub> may be split into two capacitors. One should be a larger value, based on equivalent load capacitance, and the other a smaller value, such as 1-10 nF mounted closest to the VDD and GND pins to carry the higherfrequency components of the current pulses. The bypass capacitor must provide the pulsed current from both of the driver channels and, if the drivers are sw itching simultaneously, the combined peak current sourced from the C<sub>BYP</sub> w ould be twice as large as when a single channel is sw itching.

#### **Layout and Connection Guidelines**

The FA N3213 and FAN3214 gate drivers incorporate fast-reacting input circuits, short propagation delays, and pow erful output stages capable of delivering current peaks over 4 A to facilitate voltage transition times from under 10 ns to over 150 ns. The follow ing layout and connection guidelines are strongly recommended:

- Keep high-current output and pow er ground paths separate from logic input signals and signal ground paths. This is especially critical for TTL-level logic thresholds at driver input pins.
- Keep the driver as close to the load as possible to minimize the length of high-current traces. This reduces the series inductance to improve highspeed sw itching, w hile reducing the loop area that can radiate EMI to the driver inputs and surrounding circuitry.
- If the inputs to a channel are not externally connected, the internal 100  $k\Omega$  resistors indicated on block diagrams command a low output. In noisy environments, it may be necessary to tie inputs of an unused channel to VDD or GND using short traces to prevent noise from causing spurious output sw itching.
- Many high-speed pow er circuits can be susceptible to noise injected from their ow n output or other external sources, possibly causing output retriggering. These effects can be obvious if the circuit is tested in breadboard or non-optimal circuit layouts w ith long input or output leads. For best results, make connections to all pins as short and direct as possible.
- FAN3213 and FAN3214 are pin-compatible w ith many other industry-standard drivers.
- The turn-on and turn-off current paths should be minimized, as discussed in the follow ing section.

Figure 29 show s the pulsed gate drive current path when the gate driver is supplying gate charge to turn the MOSFET on. The current is supplied from the local bypass capacitor, C<sub>BYP</sub>, and flow s through the driver to the MOSFET gate and to ground. To reach the high peak currents possible, the resistance and inductance in the path should be minimized. The localized C<sub>BYP</sub> acts to contain the high peak current pulses w ithin this driver-MOSFET circuit, preventing them from disturbing the sensitive analog circuitry in the PWM controller.



Figure 30 show s the current path w hen the gate driver turns the MOSFET OFF. Ideally, the driver shunts the current directly to the source of the MOSFET in a small circuit loop. For fast turn-off times, the resistance and inductance in this path should be minimized.



**Figure 30. Current Path for MOSFET Turn-Off**

#### **Operational Waveforms**

At pow er-up, the driver output remains LOW until the V<sub>DD</sub> voltage reaches the turn-on threshold. The  $magnitude$  of the OUT pulses rises with  $V_{DD}$  until steady-state V<sub>DD</sub> is reached. The non-inverting operation illustrated in Figure 31 shows that the output remains LOW until the UVLO threshold is reached, then the output is in-phase w ith the input.



**Figure 31. Non-Inverting Startup Waveforms**



The inverting configuration of startup w aveforms are show n in Figure 32. With IN+ tied to V DD and the input signal applied to IN–, the OUT pulses are inverted w ith respect to the input. At pow er-up, the inverted output remains LOW until the  $V_{DD}$  voltage reaches the turn-on threshold, then it follow s the input w ith inverted phase.

**Figure 32. Inverting Startup Waveforms**

#### **Thermal Guidelines**

Gate drivers used to sw itch MOSFETs and IGBTs at high frequencies can dissipate significant amounts of pow er. It is important to determine the driver pow er dissipation and the resulting junction temperature in the application to ensure that the part is operating w ithin acceptable temperature limits.

The total pow er dissipation in a gate driver is the sum of tw o components, P<sub>GATE</sub> and P<sub>DYNAMIC</sub>:

$$
Protal = PGATE + PDYNAMIC \t(1)
$$

PGATE (Gate Driving Loss): The most significant pow er loss results from supplying gate current (charge per unit time) to sw itch the load MOSFET on and off at the sw itching frequency. The pow er dissipation that results from driving a MOSFET at a specified gatesource voltage,  $V_{GS}$ , with gate charge,  $Q_G$ , at sw itching frequency, f<sub>SW</sub>, is determined by:

$$
P_{GATE} = Q_G \cdot V_{GS} \cdot f_{SW} \cdot n \tag{2}
$$

w here n is the number of driver channels in use (1 or 2).

PDYNAMIC (Dynamic Pre-Drive / Shoot-through Current): A pow er loss resulting from internal current consumption under dynamic operating conditions, including pin pull-up / pull-dow n resistors. The internal current consumption (IDYNAMIC) can be estimated using the graphs in Figure 10 of the Typical Performance Characteristics to determine the current I<sub>DYNAMIC</sub> draw n from  $V_{DD}$  under actual operating conditions:

$$
P_{DYNAMIC} = I_{DYNAMIC} \cdot V_{DD} \cdot n \tag{3}
$$

where n is the number of driver ICs in use. Note that n is usually be one IC even if the IC has two channels, unless two or more.driver ICs are in parallel to drive a large load.

Once the pow er dissipated in the driver is determined, the driver junction rise w ith respect to circuit board can be evaluated using the follow ing thermal equation, assuming  $\psi_{JB}$  w as determined for a similar thermal design (heat sinking and air flow ):

 $T_J = P_{\text{TOTAL}} \cdot \Psi_{JB} + T_B$  (4)

w here:

- $T_J$  = driver junction temperature;
- $V_{\text{JB}}$  = (psi) thermal characterization parameter relating temperature rise to total pow er dissipation; and
- $T_B$  = board temperature in location as defined in the Thermal Characteristics table.

To give a numerical example, assume for a 12 V V DD (Vibas) system, the synchronous rectifier sw itches of Figure 33 have a total gate charge of 60 nC at  $V_{GS}$  = 7 V. Therefore, two devices in parallel w ould have 120 nC gate charge. At a sw itching frequency of 300 kHz, the total pow er dissipation is:

 $P_{GATE} = 120 nC \cdot 7 V \cdot 300 kHz \cdot 2 = 0.504 W$  (5)

 $P_{DYNAMIC} = 3.0 \text{ mA} \cdot 12 \text{ V} \cdot 1 = 0.036 \text{ W}$  (6)

$$
Protal = 0.540 W \tag{7}
$$

The SOIC-8 has a junction-to-board thermal characterization parameter of  $\Psi_{JB} = 42^{\circ}$ C/W. In a system application, the localized temperature around the device is a function of the layout and construction of the PCB along w ith airflow across the surfaces. To ensure reliable operation, the maximum junction temperature of the device must be prevented from exceeding the maximum rating of 150°C; w ith 80% derating, T<sup>J</sup> w ould be limited to 120°C. Rearranging Equation 4 determines the board temperature required to maintain the junction temperature below 120°C:

$$
T_{B,MAX} = T_J - P_{TOTAL} \cdot \psi_{JB}
$$
 (8)

$$
T_{B,MAX} = 120^{\circ}\text{C} - 0.54 \text{ W} \cdot 42^{\circ}\text{C/W} = 97^{\circ}\text{C}
$$
 (9)



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#### **Table 1. Related Products**

**Notes:**

15. Typical currents with OUTx at 6 V and  $V_{DD}$ =12 V.

16. Thresholds proportional to an externally supplied reference voltage.



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